

SI7457DP-VB Datasheet P-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
- 100	0.032 at V _{GS} = - 10 V	- 28	7.6 nC			
- 100	0.036 at V _{GS} = - 4.5 V	- 25	7.6110			

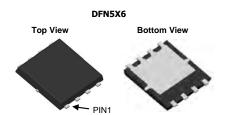
FEATURES

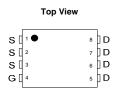
- Trench Power MOSFET
- 100 % UIS Tested

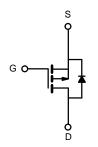
APPLICATIONS

Load Switch









P-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 100	.,		
Gate-Source Voltage	V_{GS}	± 20	V		
	T _C = 25 °C		- 28 ^a		
Continuous Drain Current (T = 150 °C)	T _C = 70 °C		- 27		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	22.2 ^b	A	
	T _A = 70 °C		- 26.1 ^b		
Pulsed Drain Current		I _{DM}	- 15		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	- 4.5		
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	10.1	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	1	6.9 ^a		
Continuous Source-Diain Diode Current	T _A = 25 °C	I _s —	2.1 ^b	A	
	T _C = 25 °C		10.4 ^a		
Maximum Power Dissipation	T _C = 70 °C	D	6.6 ^a		
	T _A = 25 °C	P _D —	1.1 ^b	W	
	T _A = 70 °C		2 ^b		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^b	Steady State	R_{thJA}	33	40	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	0.98	1.2]		

Notes:

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.



Parameter Symbol Test Co		Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 100			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		68		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	i _D = - 250 μA		- 5.2		mv/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.8		- 3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zara Cata Valtaga Drain Current	١.	V _{DS} = - 100 V, V _{GS} = 0 V			- 1		
Zero Gate Voltage Drain Current	IDSS	V _{DS} = - 100 V, V _{GS} = 0 V, T _J = 55 °C			- 10	μA	
On-State Drain Current ^a	I _{D(on)}	V _{DS} = - 5 V, V _{GS} = - 10 V	- 120			Α	
D : 0	В	V _{GS} = - 10 V, I _D = - 3 A		0.032		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, I_D = -2 \text{ A}$		0.036			
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 5 A	20			S	
Dynamic ^b							
Input Capacitance	C _{iss}			3500			
Output Capacitance	C _{oss}	V _{DS} = - 25 V, V _{GS} = 0 V, f = 1 MHz		390		pF	
Reverse Transfer Capacitance	C _{rss}			290		•	
Total Cata Charge	Qg	$V_{DS} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -5 \text{ A}$		76	115	20	
Total Gate Charge				38	60		
Gate-Source Charge	Q _{gs}			16		nC	
Gate-Drain Charge	Q_{gd}			19		1	
Gate Resistance	R_g	f = 1 MHz		5.2		Ω	
Turn-On Delay Time	t _{d(on)}			10	15		
Rise Time	t _r	$V_{DD} = -2 V$, $R_L = 2 \Omega$		7	15	ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 5 A, V_{GEN} = - 10 V, R_g = 1 Ω		70	110		
Fall Time	t _f			40	60		
Drain-Source Body Diode Characteristics	s						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			- 6.9	Α	
Pulse Diode Forward Current ^a	I _{SM}				- 15	^	
Body Diode Voltage	V _{SD}	I _S = - 3 A		- 1	- 1.5	V	
Body Diode Reverse Recovery Time	t _{rr}			45	68	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	-		59	120	nC	
Reverse Recovery Fall Time	t _a	$I_F = -5 \text{ A}, \text{ di/dt} = 10 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		29		-	
Reverse Recovery Rise Time	t _b			16		ns	

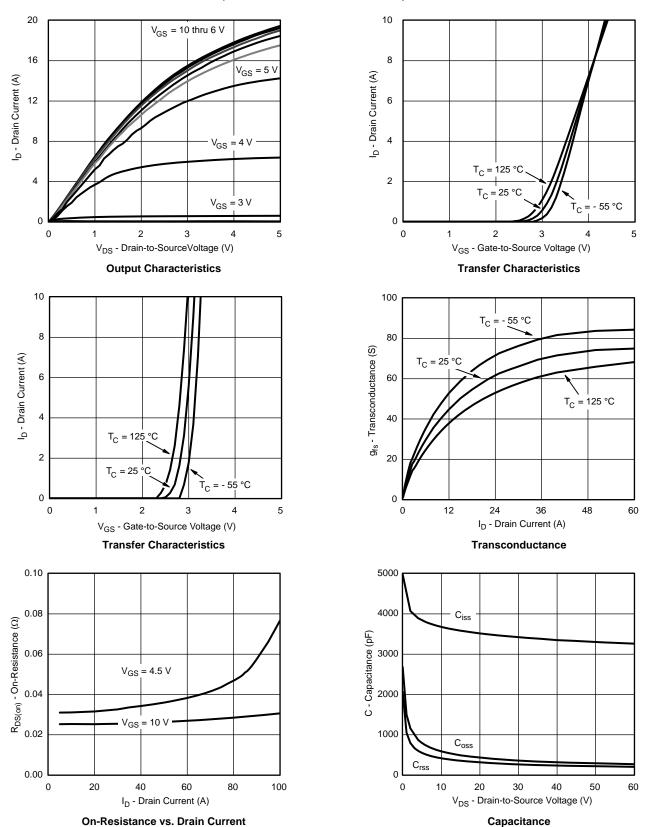
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

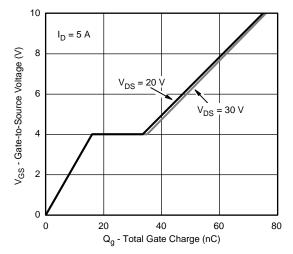


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

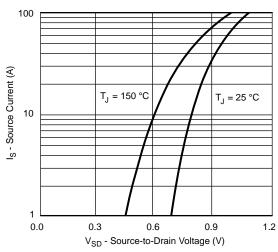




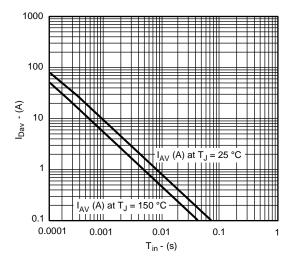
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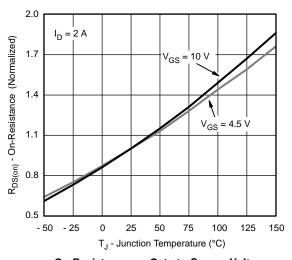
Gate Charge



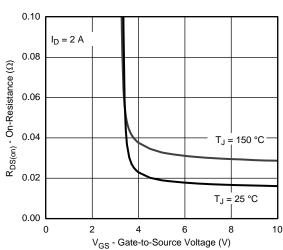
Source-Drain Diode Forward Voltage



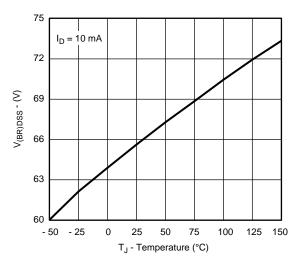
Single Pulse Avalanche Current Capability vs. Time



On-Resistance vs. Gate-to-Source Voltage



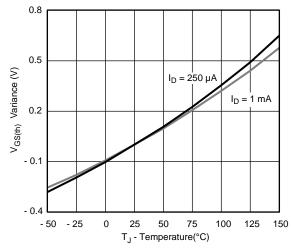
On-Resistance vs. Gate-to-Source Voltage

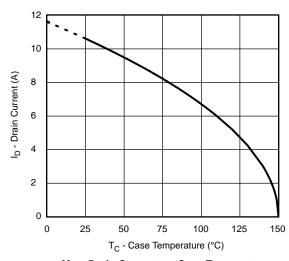


Drain-Source Breakdown Voltage vs. Junction Temperature

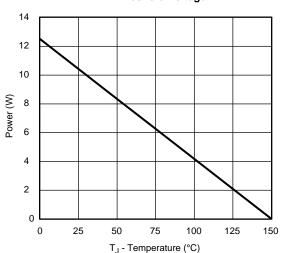


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

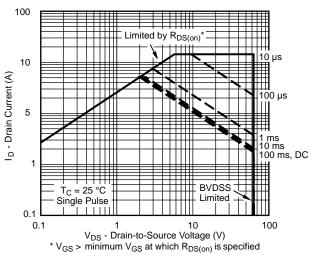




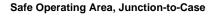
Threshold Voltage

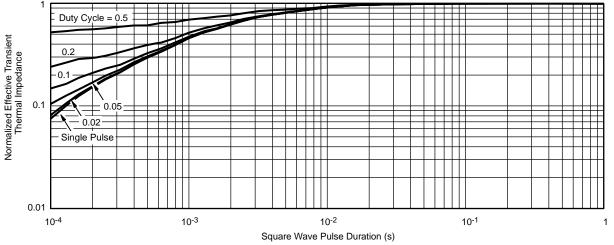


Max. Drain Current vs. Case Temperature



Power Derating, Junction-to-Case

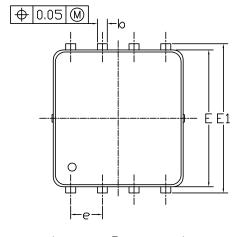


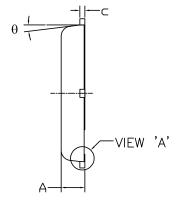


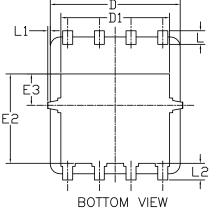
Normalized Thermal Transient Impedance, Junction-to-Case

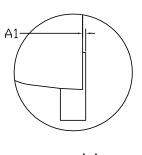


DFN5x6_8L_EP1_P PACKAGE OUTLIN



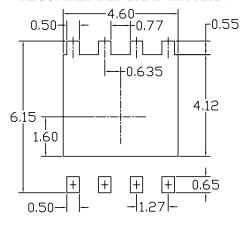






<u>VIEW 'A'</u> (SCALE 5:1)

RECOMMENDED LAND PATTERN



arn mora	SYMBOLS DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
3 I MBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
A	0.85	0. 95	1.00	0.033	0. 037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
С	0.15	0. 20	0. 25	0.006	0.008	0.010	
D	5. 10	5. 20	5. 30	0. 201	0. 205	0. 209	
D1	4. 25	4. 35	4. 45	0. 167	0.171	0. 175	
Е	5. 45	5. 55	5. 65	0. 215	0.219	0. 222	
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242	
E2	3. 525	3. 625	3. 725	0. 139	0. 143	0. 147	
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054	
e	1. 27 BSC			0.050 BSC			
L	0.45	0. 55	0.65	0.018	0.022	0.026	
L1	0		0. 15	0		0.006	
L2	0.68 REF			0. 027 REF			
θ	0°		10°	0°		10°	

NOTE

- UNIT: mm
- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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